

Application/Control No.	Applicant(s)/Patent under Reexamination
10/646,955	CHEN ET AL.
Examiner	Art Unit
David O. Nguyen	2681

	SEARCHED				
Class	Subclass	Date	Examiner		
370	379	10/19/05	m		
	340				
	229				
	230,1				
	230,1				
	w				
	vsg				
	341				
	321				
	321				
	335				
	315,41				
300	941				
455	454	10/17/15	W		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East search.	40/18/8	m		